

Search Notes



Application/Control No.

10/768,615

Examiner

Tse Chen

Applicant(s)/Patent under
Reexamination

ARTMAN ET AL.

Art Unit

2116

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
text search only see "rpt protot"		TSC
713/340 WITH "REDUNDANT", "ARRAY"	10/26/06	TSC